Machine Learning Methods in Software Engineering

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Deadline for manuscript submissions:
15 July 2024

Message from the Guest Editors

Dear Colleagues,

Currently, the modern digital economy and society rely on software systems. Many software development projects fail or struggle to finish on time within budget.

Software engineering is challenged with fast changes in project objectives, constraints, or priorities. Changes in competitive threats, technology, organizations, leadership priorities, and environments must be incorporated into the software engineering process. The involvement of machine learning can improve strategies such as incremental and evolutionary development, which brings new issues from requirements to the sizing of new projects. Contributions scope may include topics such as:

- neural networks, including a deep neural network in software engineering;
- deep learning and other artificial algorithms for predictions in software engineering;
- clustering methods in software engineering;
- bio-inspired algorithms and their application;
- fuzzy sets;
- machine learning and AI application in project effort estimation;
- mathematical statistics and AI applications in testing and software quality.

The contribution may be related to the whole software development lifecycle.

mdpi.com/si/143189

Special Issue

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Message from the Editor-in-Chief

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